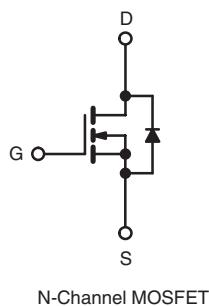
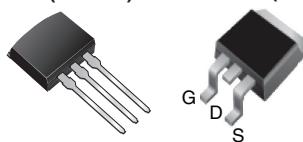


Power MOSFET

PRODUCT SUMMARY		
V _{DS} (V)	60	
R _{DS(on)} (Ω)	V _{GS} = 10 V	0.10
Q _g (Max.) (nC)	25	
Q _{gs} (nC)	5.8	
Q _{gd} (nC)	11	
Configuration	Single	

I²PAK (TO-262) D²PAK (TO-263)


N-Channel MOSFET

FEATURES

- Advanced Process Technology
- Surface Mount (IRFZ24S/SiHFZ24S)
- Low-Profile Through-Hole (IRFZ24L/SiHFZ24L)
- 175 °C Operating Temperature
- Fast Switching
- Lead (Pb)-free Available


RoHS*
COMPLIANT

DESCRIPTION

Third generation Power MOSFETs from Vishay utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The D²PAK is a surface mount power package capable of accommodating die size up to HEX-4. It provides the highest power capability and the lowest possible on-resistance in any existing surface mount package. The D²PAK is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0 W in a typical surface mount application. The through-hole version (IRFZ24L/SiHFZ24L) is available for low-profile applications.

ORDERING INFORMATION

Package	D ² PAK (TO-262)	D ² PAK (TO-262)	I ² PAK (TO-263)
Lead (Pb)-free	IRFZ24SPbF	-	-
	SiHFZ24S-E3	-	-
SnPb	IRFZ24S	IRFZ24STRL ^a	IRFZ24L
	SiHFZ24S	SiHFZ24STL ^a	SiHFZ24L

Note

a. See device orientation.

ABSOLUTE MAXIMUM RATINGS T_C = 25 °C, unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V _{DS}	60	
Gate-Source Voltage	V _{GS}	± 20	V
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	I _D
		T _C = 100 °C	
Pulsed Drain Current ^{a, e}	I _{DM}	68	A
Linear Derating Factor		0.40	W/°C
Single Pulse Avalanche Energy ^{b, e}	E _{AS}	100	mJ
Maximum Power Dissipation	T _C = 25 °C	60	P _D
		3.7	
Peak Diode Recovery dV/dt ^{c, e}	dV/dt	4.5	V/ns
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 175	°C
Soldering Recommendations (Peak Temperature)	for 10 s	300 ^d	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. V_{DD} = 25 V, starting T_J = 25 °C, L = 400 μH, R_G = 25 Ω, I_{AS} = 17 A (see fig. 12).

c. I_{SD} ≤ 17 A, dI/dt ≤ 140 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 175 °C.

d. 1.6 mm from case.

e. Uses IRFZ24/SiHFZ24 data and test conditions.

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient (PCB Mounted, Steady-State) ^a	R _{thJA}	-	40	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	2.5	

Note

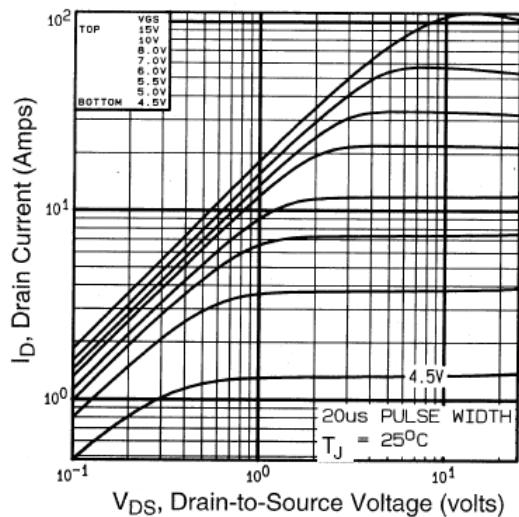
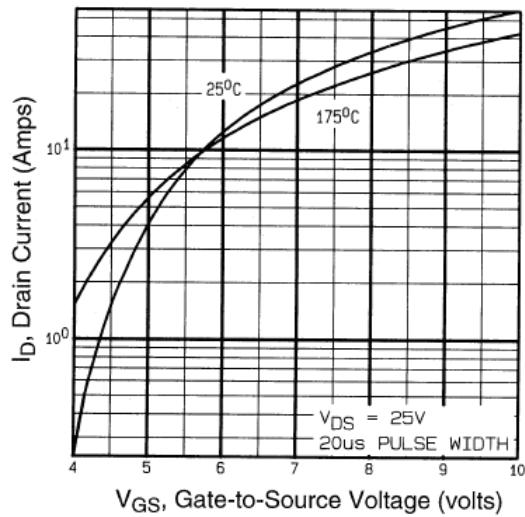
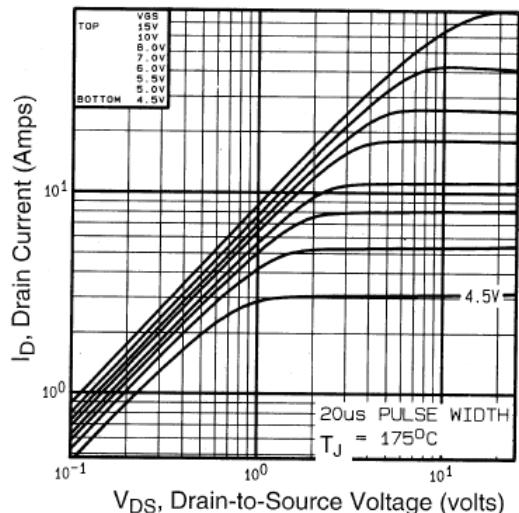
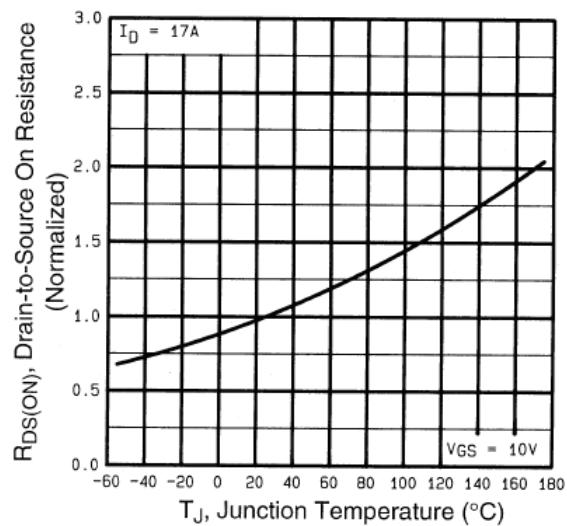
- a. When mounted on 1" square PCB (FR-4 or G-10 material).

SPECIFICATIONS T_J = 25 °C, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA		60	-	-	V
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	Reference to 25 °C, I _D = 1 mA ^c		-	0.061	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA		2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 60 V, V _{GS} = 0 V		-	-	25	μA
		V _{DS} = 48 V, V _{GS} = 0 V, T _J = 150 °C		-	-	250	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 10 A ^b	-	-	0.10	Ω
Forward Transconductance	g _{fs}	V _{DS} = 25 V, I _D = 10 A ^d		5.5	-	-	S
Dynamic							
Input Capacitance	C _{iss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1.0 MHz, see fig. 5 ^d		-	640	-	pF
Output Capacitance	C _{oss}			-	360	-	
Reverse Transfer Capacitance	C _{rss}			-	79	-	
Total Gate Charge	Q _g	V _{GS} = 10 V	I _D = 17 A, V _{DS} = 48 V, see fig. 6 and 13 ^{b, c}	-	-	25	nC
Gate-Source Charge	Q _{gs}			-	-	5.8	
Gate-Drain Charge	Q _{gd}			-	-	11	
Turn-On Delay Time	t _{d(on)}			-	13	-	
Rise Time	t _r	V _{DD} = 30 V, I _D = 17 A, R _G = 18 Ω, R _D = 1.7 Ω, see fig. 10 ^{b, c}		-	58	-	ns
Turn-Off Delay Time	t _{d(off)}		-	25	-		
Fall Time	t _f		-	42	-		
Internal Source Inductance	L _S	Between lead, and center of die contact		-	7.5	-	nH
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	17	A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	68	
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 17 A, V _{GS} = 0 V ^b		-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 17 A, dI/dt = 100 A/μs ^{b, c}		-	88	180	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	290	640	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)					

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 μs; duty cycle ≤ 2 %.
c. Uses IRFZ24/SiHFZ24 data and test conditions.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Fig. 1 - Typical Output Characteristics, $T_c = 25^\circ\text{C}$

Fig. 3 - Typical Transfer Characteristics

Fig. 2 - Typical Output Characteristics, $T_c = 175^\circ\text{C}$

Fig. 4 - Normalized On-Resistance vs. Temperature

IRFZ24S, IRFZ24L, SiHFZ24S, SiHFZ24S

Vishay Siliconix

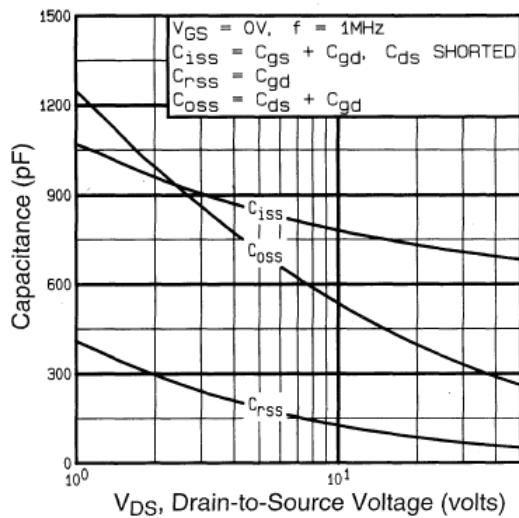


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

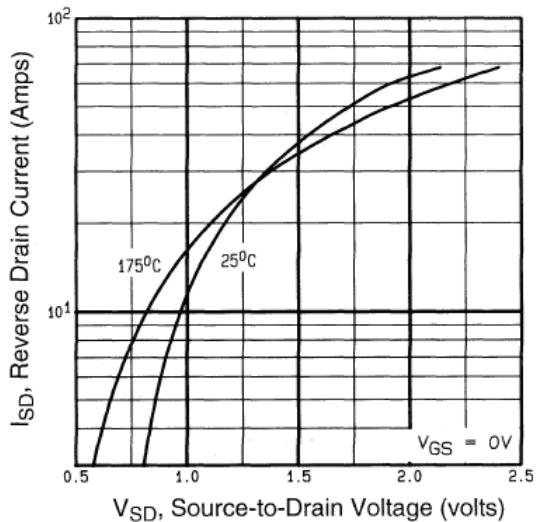


Fig. 7 - Typical Source-Drain Diode Forward Voltage

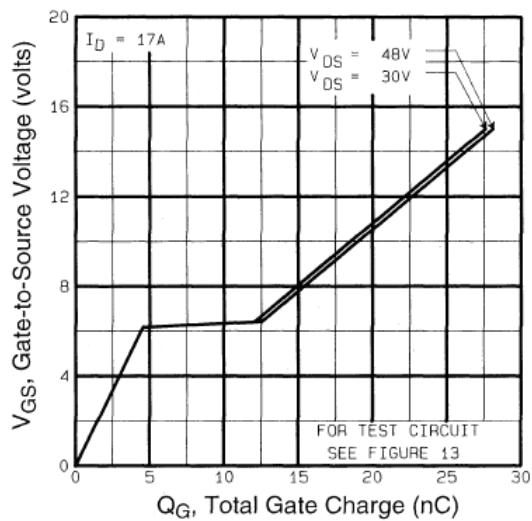


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

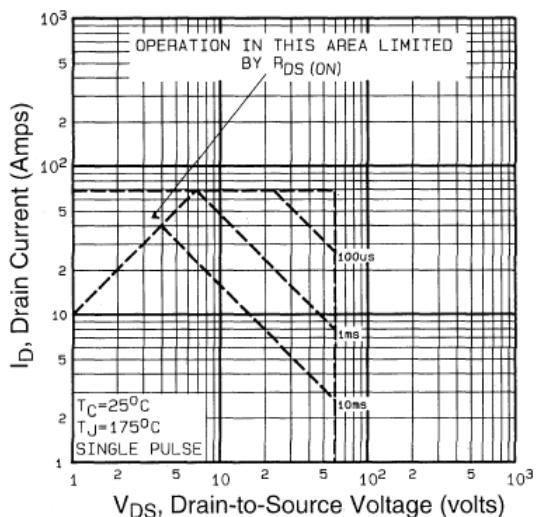


Fig. 8 - Maximum Safe Operating Area

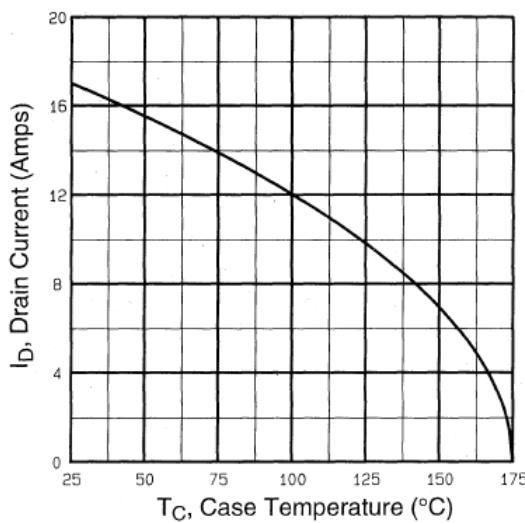


Fig. 9 - Maximum Drain Current vs. Case Temperature

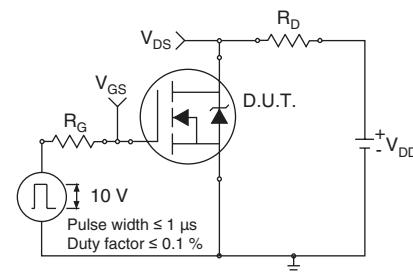


Fig. 10a - Switching Time Test Circuit

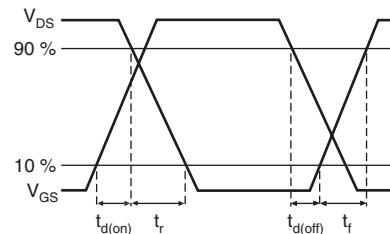


Fig. 10b - Switching Time Waveforms

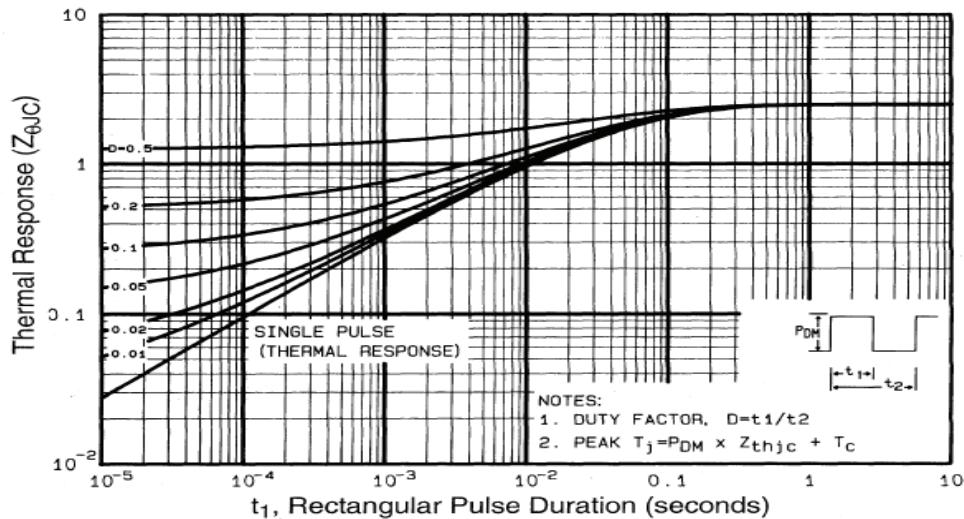


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

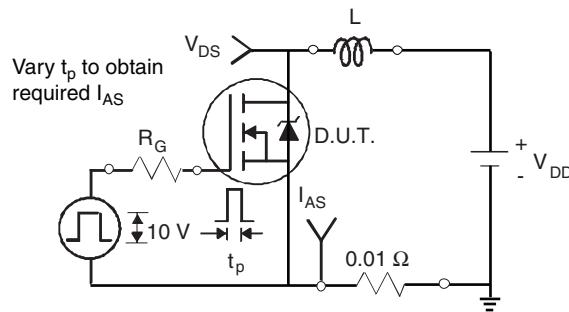


Fig. 12a - Unclamped Inductive Test Circuit

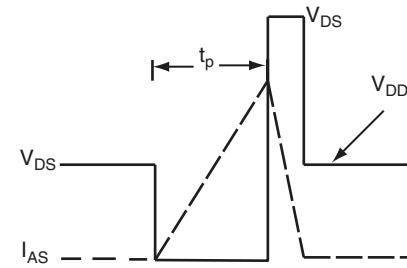


Fig. 12b - Unclamped Inductive Waveforms

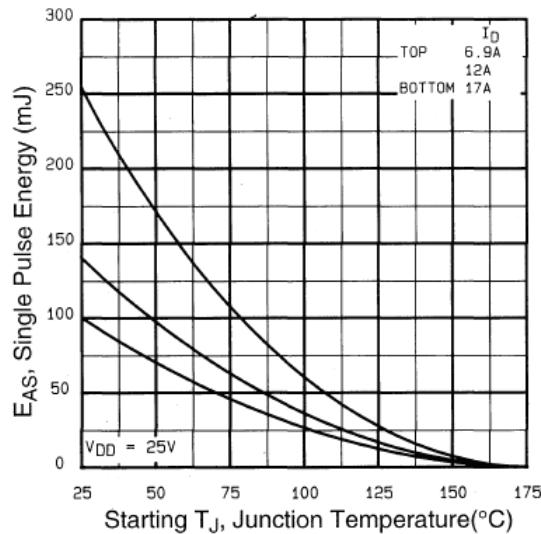


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

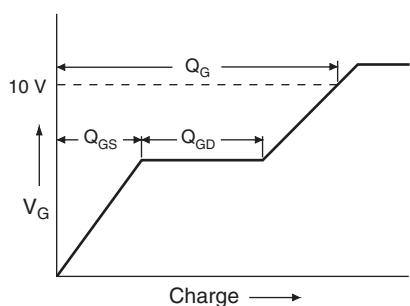


Fig. 13a - Basic Gate Charge Waveform

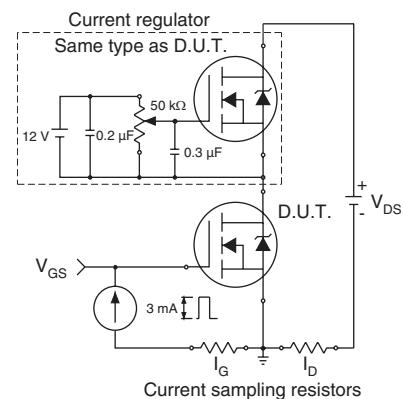
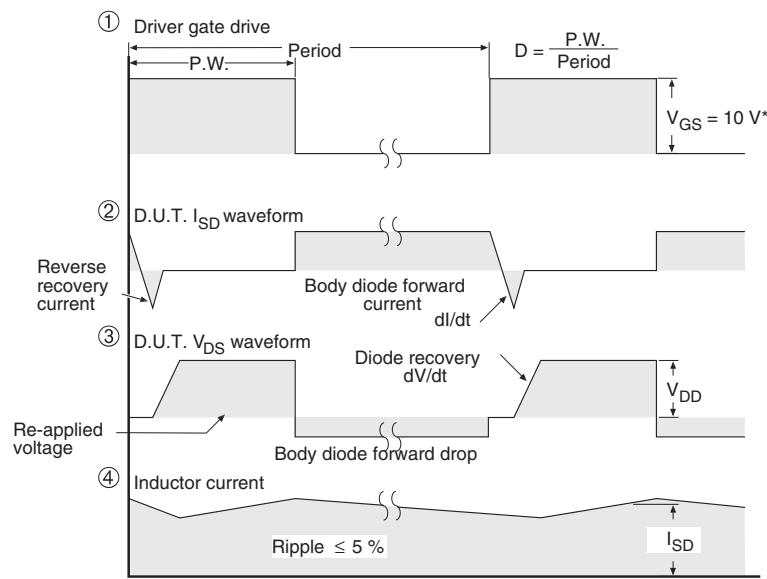
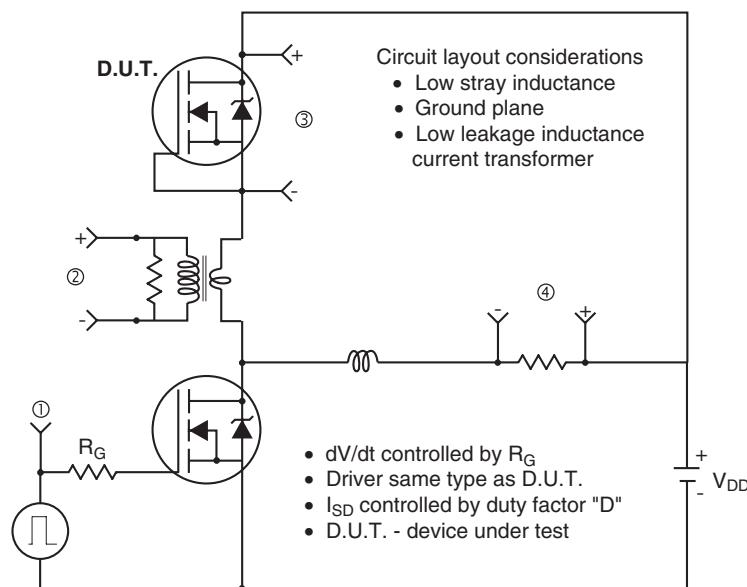


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel

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